SN74CBT3253 DUAL 4-BIT TO 1-BIT FET MULTIPLEXER/DEMULTIPLEXER

1OE

S1 2

1B4 🛿 3

1B3 🛛 4

1B2 🛛 5

1B1 🛛 6

1A 🛛 7

GND 8

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16 VCC

15 20E

14 🛛 S0

13 2B4

12 🛛 2B3

11 2B2 10 2B1

9 🛛 2A

D, DB, DBQ, OR PW PACKAGE (TOP VIEW)

- Functionally Equivalent to QS3253
- 5-Ω Switch Connection Between Two Ports
- TTL-Compatible Control Input Levels
 Package Options Include Plastic Small-Outline (D), Shrink Small-Outline
- (DB), Quarter-Size Small-Outline (DBQ), and Thin Shrink Small-Outline (PW) Packages

description

The SN74CBT3253 is a dual 4-bit to 1-bit high-speed TTL-compatible FET multiplexer/ demultiplexer. The low on-state resistance of the switch allows connections to be made with minimal propagation delay.

10E, 20E, S0, and S1 select the appropriate B output for the A-input data.

The SN74CBT3253 is characterized for operation from -40°C to 85°C.

TONOTION TABLE								
S1	S0	1 <mark>0E</mark>	2 <mark>0E</mark>	FUNCTION				
Х	Х	Х	Н	Disconnect 1A				
Х	х	н	х	Disconnect 2A				
L	L	L	L	A = B1				
L	Н	L	L	A = B2				
Н	L	L	L	A = B3				
Н	Н	L	L	A = B4				

FUNCTION TABLE



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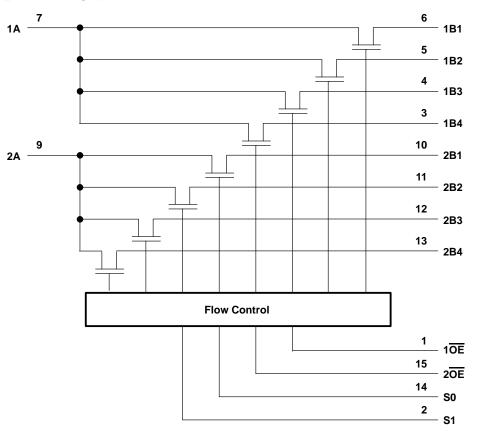
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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC} Input voltage range, V _I (see Note 1)		
Continuous channel current		
Input clamp current, I _K (V _{I/O} < 0)		
Package thermal impedance, θ_{JA} (see Note 2)): D package	113°C/W
	DB package	131°C/W
	DBQ package	139°C/W
	PW package	149°C/W
Storage temperature range, T _{stg}		. –65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

recommended operating conditions

		MIN	MAX	UNIT
V _{CC}	Supply voltage	4	5.5	V
VIH	High-level control input voltage	2		V
VIL	Low-level control input voltage		0.8	V
Τ _Α	Operating free-air temperature	-40	85	°C



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			MIN	TYP [†]	MAX	UNIT	
VIK		V _{CC} = 4.5 V,	lı = -18 mA				-1.2	V	
lj		V _{CC} = 5 V,	VI = 5.5 V or GND				±1	μA	
ICC		V _{CC} = 5.5 V,	l _O = 0,	$V_{I} = V_{CC}$ or GND			3	μA	
ΔI_{CC}^{\ddagger}	Control pins	V _{CC} = 5.5 V,	One input at 3.4 V,	Other inputs at V_{CC} or GND			2.5	mA	
Ci	Control pins	V _I = 3 V or 0				3.5		pF	
C:	A port	V _O = 3 V or 0,				10		pF	
C _{io(OFF)}	B port		$\overline{OE} = V_{CC}$			4		рг	
8		$V_{CC} = 4 V,$	V _I = 2.4 V,	lj = 15 mA					
			$V_{I} = 0$	lj = 64 mA		5	7	Ω	
r _{on} §		$V_{CC} = 4.5 V$	v] = 0	II = 30 mA		5	7	52	
			V _I = 2.4 V,	l _l = 15 mA		10	15]	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡]This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

§ Measured by the voltage drop between the A and the B terminals at the indicated current through the switch. On-state resistance is determined by the lower voltage of the two (A or B) terminals.

switching characteristics over recommended operating free-air temperature range, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

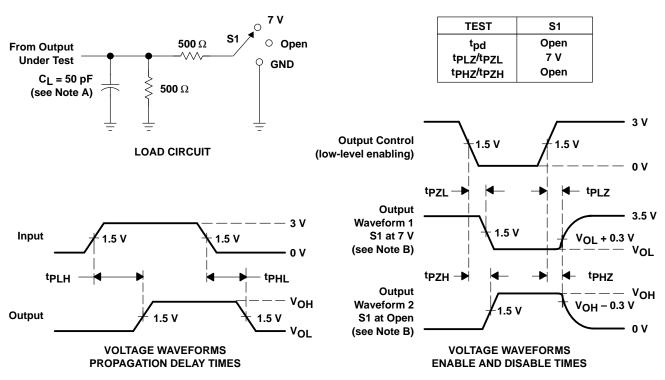
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V ± 0.5 V		V _{CC} = 4 V		UNIT
			MIN	MAX	MIN	MAX	
t _{pd} ¶	A or B	B or A		0.25		0.25	ns
^t pd	S	A or B	1.6	6.2	1.7	6.6	ns
+	S	A or B	1.3	6.3	1.9	7.1	ns
ten	OE		1.4	6.4	2.3	7.3	
•	S	A or B	1.1	7.4	1.9	7.9	ns
tdis	OE		2.3	7	2.2	7.3	

This parameter is warranted but not production tested. The propagation delay is based on the RC time constant of the typical on-state resistance of the switch and a load capacitance of 50 pF, when driven by an ideal voltage source (zero output impedance).



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

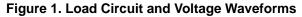
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns. D. The outputs are measured one at a time with one transition per measurement.

D. The outputs are measured one at a time with

- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en} . G. t_{PLH} and t_{PHL} are the same as t_{pd} .

G. IPLH and IPHL are the same as Ipd.





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